SHEET 1 OF 1

Substitute for forms 1449A/PTO & 1449B/PTO

FIRST INFORMATION DISCLOSURE STATEMENT BY APPLICANT

ATTORNEY'S DKT No. 007413-056	APPLICATION No. 10/614,825
APPLICANT Oliver KIENZLE et al.	
FILING DATE July 9, 2003	GROUP Unassigned

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Examiner Signature	Zia R-HASHMI	Date Considered	12/27/04

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